

Features

- 0603 SMD LED
- Close responsively to the human eye spectrum
- Light to Current, analog output
- Good output linearity across wide illumination range
- Low sensitivity variation across various light sources

Applications

- Infrared application system
- Optoelectronic automatic control system
- Optoelectronic switch
- Printer
- Counters and sorters
- Encoders
- Floppy disk drive
- Video camera, tape and card readers
- Position sensors

Description

The IN-S63DTPT is a popular 0603 package with versatile design capabilities. It is a PCB type LED which can be used in various applications. Due to its clear epoxy, the device is matched to visible light and infrared radiation.

Recommended Solder Pattern

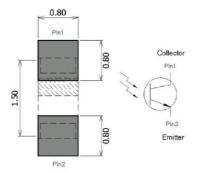
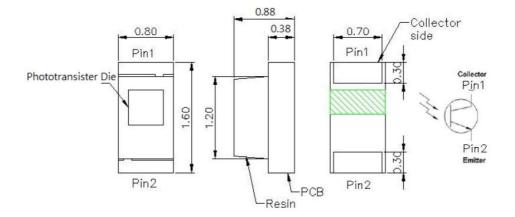


Figure 1. IN-S63DTPT Solder Pattern

Package Dimensions in mm



Notes.

- 1. All dimensions are in millimeters.
- 2. Tolerance is ± 0.10 mm unless otherwise noted

Figure 2. IN-S63DTPT Package Dimensions



Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
BVCEO	Collector-Emitter Breakdown Voltage	35	V	1
BVECO	Emitter-Collector Breakdown Voltage	5	V	2
lc	Collector Current	20	mA	
Topr	Operating Temperature	-40~+85	°C	
Tstg	Storage Temperature	-40~+100	°C	
Tsol	Soldering Temperature	260	°C	3
Pto	Total Power Dissipation	150	mW	

Notes

- 1. Test conditions: Ic=100µA, E_e=0mW/cm₂.
- 2. Test conditions: $I_E=100\mu A$, $E_e=0mW/cm_2$.
- 3. Soldering time \leq 5 seconds.

ESD Precaution

ATTENTION: Electrostatic Discharge (ESD) protection



The symbol above denotes that ESD precaution is needed. ESD protection for GaP and AlGaAs based chips is necessary even though they are relatively safe in the presence of low static-electric discharge. Parts built with AllnGaP, GaN, or/and InGaN based chips are STATIC SENSITIVE devices. ESD precaution must be taken during design and assembly.

If manual work or processing is needed, please ensure the device is adequately protected from ESD during the process.

Please be advised that normal static precautions should be taken in the handling and assembly of this device to prevent damage or degradation which may be induced by electrostatic discharge (ESD).

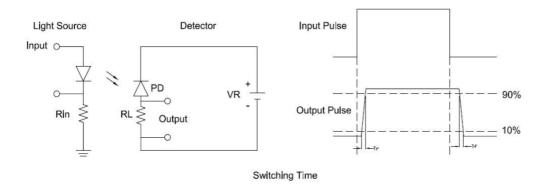


Electro-Optical Characteristics

Symbol	Parameters	Test conditions	Min	Тур	Max	Units	Notes
λD	Rang Of Spectral Bandwidth		400	-	1100	nm	
λР	Wavelength Of Peak Sensitivity		-	940		nm	
BVCEO	Collector-Emitter Breakdown Voltage	Ic=100µA E _e =0mW/cm²	-	35	-	V	
BVECO	Emitter-Collector Breakdown Voltage	I _E =100µA E _e =0mW/cm²	-	5	-	V	
VCE(sat)	Collector-Emitter Saturation Voltage	Ic=2mA Ee=1mW/cm²	-	-	0.4	V	
ICEO	Collector Dark Current	VCE=20V Ee=0mW/cm²	-	-	100	nA	
IC(ON)	On State Collector Current	Ee=1mW/cm ² λ_P =940nm, V_{CE} =5V	0.9	1.2	2.42	mA	
tr	Rise Time	Vce=5V, Ic=1mA	-	15	-	uS	4
tf	Fall Time	IC= IMA RL=1000Ω	-	15	-	uS	4

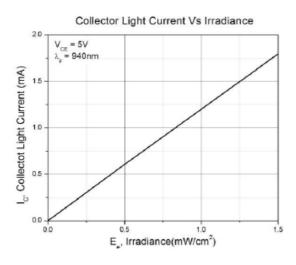
Notes

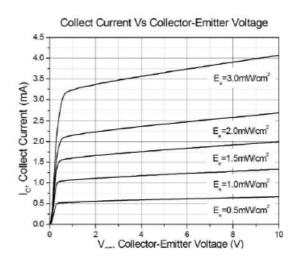
4. Test circuit:

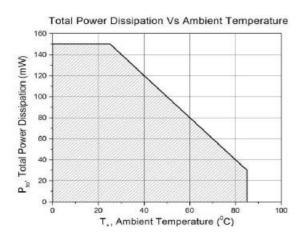


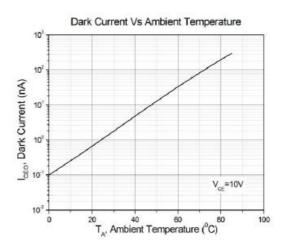


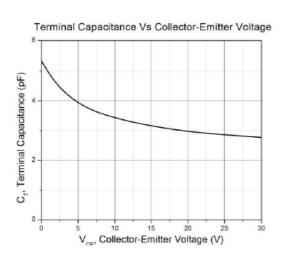
Typical Characteristic Curves

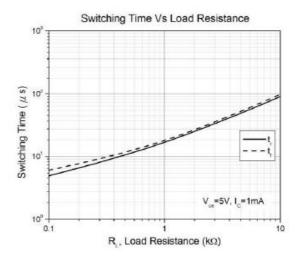










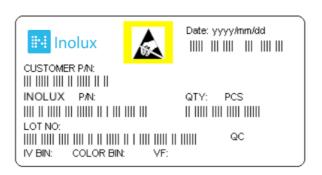




Ordering Information

Product	Symbol	Parameters	Test conditions	Min	Тур	Max	Units	Orderable Part Number
IN-S63DTPT	IC(ON)	On State Collector Current	Ee=1mW/cm ² λ_P =940nm, V_{CE} =5V	0.9	1.2	2.42	mA	IN-S63DTPT

Label Specifications



Inolux P/N:

ı	Ν	1	S	6	3	D	Т		PT	-	-	-		-
			Material	Pacl	kage	Variation	Orientation	Lens	Color				miz 1p-o	
Ino SM			PCB - S	63D	= 0603	3 0.88mm	T = Top Mount	(Blank) = Clear U = Diffused	PT = Photo Transistor					

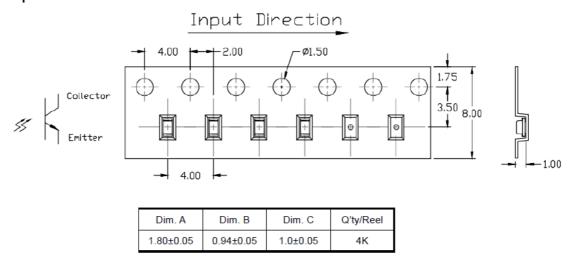
Lot No.:

Z	2	0	1	7	01	24	001
Internal Tracker	Year (2017, 2018,)				Month	Date	Serial

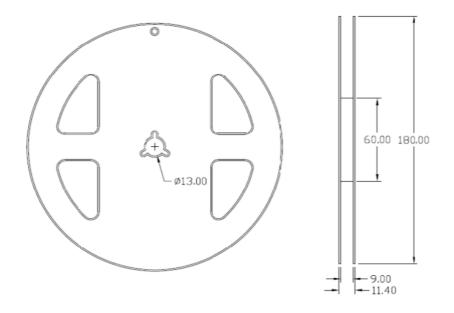


Packaging Information:

Packaging Tape Dimension

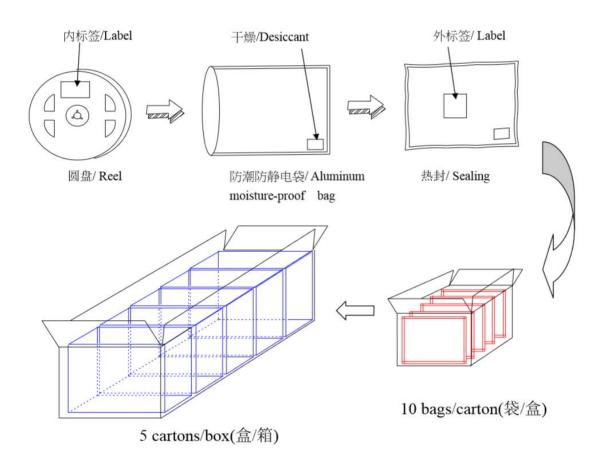


Reel Dimension



Packing Dimension





5 boxes per carton are available depending on shipment quantity.

	Specification	Material	Quantity
Carrier tape	Per EIA 481-1A specs	Conductive black tape	4000pcs per reel
Reel	Per EIA 481-1A specs	Conductive black	
Label	IN standard	Paper	
Packing bag	220x240mm	Aluminum laminated bag/ no-zipper	One reel per bag
Carton	IN standard	Paper	Non-specified
Otherno			

Others:

Each immediate box consists of 5 reels. The 5 reels may not necessarily have the same lot number or the same bin. Each reel has a label identifying its specification; the immediate box consists of a product label as well.

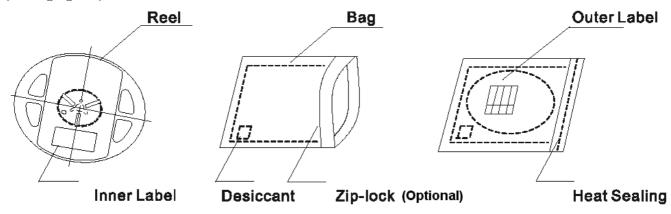


Dry Pack

All SMD optical devices are **MOISTURE SENSITIVE**. Avoid exposure to moisture at all times during transportation or storage. Every reel is packaged in a moisture protected anti-static bag. Each bag is properly sealed prior to shipment.

Upon request, a humidity indicator will be included in the moisture protected anti-static bag prior to shipment.

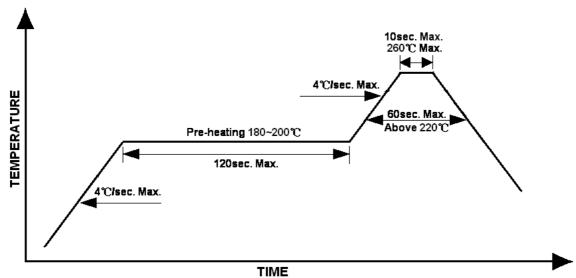
The packaging sequence is as follows:



Reflow Soldering

- Recommended tin glue specifications: melting temperature in the range of 178~192 °C
- The recommended reflow soldering profile is as follows (temperatures indicated are as measured on the surface of the LED resin):

Lead-free Solder Profile





Precautions

- Avoid exposure to moisture at all times during transportation or storage.
- Anti-Static precaution must be taken when handling GaN, InGaN, and AllnGaP products.
- It is suggested to connect the unit with a current limiting resistor of the proper size. Avoid applying a reverse voltage.
- Avoid operation beyond the limits as specified by the absolute maximum ratings.
- Avoid direct contact with the surface through which the LED emits light.
- If possible, assemble the unit in a clean room or dust-free environment.

Reworking

- Rework should be completed within 5 seconds under 260 °C.
- The iron tip must not come in contact with the copper foil.
- Twin-head type is preferred.

Cleaning

Following are cleaning procedures after soldering:

- An alcohol-based solvent such as isopropyl alcohol (IPA) is recommended.
- Temperature x Time should be 50°C x 30sec. or <30°C x 3min
- Ultra sonic cleaning: < 15W/ bath; bath volume ≤ 1liter
- Curing: 100 °C max, <3min

Cautions of Pick and Place

- Avoid stress on the resin at elevated temperature.
- Avoid rubbing or scraping the resin by any object.
- Electro-static may cause damage to the component. Please ensure that the equipment is properly grounded. Use of an ionizer fan is recommended.





Reliability

Tailures Reference For all reliability J-STD-020 1.) Baking at 85°C for 24hrs 2.) Moisture storage at 85°C/60% R.H. for 168hrs 10/1/22/0 JESD22-B102-B And CNS-5068 Tinning speed: 2.5+0.5cm/s Tinning: A: 215°C/3+1s or B: 260°C/10+1s	паршту			
For all reliability monitoring tests according to JEDEC Level 2 1.) Baking at 85°C for 24hrs 2.) Moisture storage at 85°C/ 60% R.H. for 168hrs 1Q/ 1/ 22/ 0 JESD22-B102-B Accelerated aging 155°C/ 24hrs Tinning speed: 2.5+0.5cm/s Tinning speed: 2.5+0.5cm/s Tinning speed: 2.5+0.5cm/s Tinning speed: 2.5+0.5cm/s Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s Dipping soldering terminal only Soldering bath temperature Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s	Item			Conditions
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CNS-5067 Dipping soldering terminal only Soldering bath temperature A: 2604/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s 1Q/ 1/ 40/ 0 CNS-11829 1.) Precondition: 85°C baking for 24hrs 85°C/ 60%R.H. for 168hrs 2.) Tamb25°C; IF=20mA; duration 1000hrs High humidity, high temperature bias 1Q/ 1/ 45/ 0 JESD-A101-B Tamb: 85°C Humidity: 85% R.H., IF=5mA Duration: 1000hrs High temperature bias 1Q/ 1/ 20 IN specs. Tamb: 55°C IF=20mA Duration: 1000hrs High temperature bias 1Q/ 1/ 40/ 0 JESD-A104-A Duration: 1000hrs Tamb25°C, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 \(\mu\) s,T=1sec) Duration 500hrs Temperature cycle 1Q/ 1/ 76/ 0 JESD-A104-A IEC 68-2-14, Nb In the minimal steady within 5 min 300 cycles 2 chamber/ Air-to-air type High humidity 1Q/ 1/ 40/ 0 CNS-6117 60+3°C	Solderability		And CNS-5068	
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Storage test 1 190+5/-1076 K.H. 101 300H1S	storage test	1.07 17 107 0		90+5/-10% R.H. for 500hrs
	High temperature	1Q/ 1/ 40/ 0	CNS-554	
	storage test			1557.15 3.16. 3333
	Low temperature	1Q/ 1/ 40/ 0	CNS-6118	-40+5°C for 500hrs
	storage test			





Revision History

Changes since last revision	Page	Version No.	Revision Date
Initial Release		1.0	01-31-2019

DISCLAIMER

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- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- 2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.